

New JEOL developments for High Resolution studies using Scanning & Transmission Electron Microscopes

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Since 1949, JEOL's legacy has been one of the most remarkable innovations in the development of instruments used to advance scientific research and technology. JEOL has 60 years of expertise in the field of electron microscopy, more than 50 years in mass spectrometry and NMR spectrometry, and more than 40 years of e-beam lithography leadership.

This presentation is focused on the new JEOL developments of high resolution instruments. The first part will be devoted to the Scanning Electron Microscopes (SEM) with the introduction of the latest instruments developed by JEOL and of a new kind of spectrometer for chemical state analysis called SXES (Soft X-Ray Emission Spectrometer). The second part will deal with the Transmission Electron Microscopes equipped with Cold FEG and their capabilities for high resolution analysis (TEM, STEM, EDS ...) and routine work.